

# AOD2916

# 100V N-Channel MOSFET

# **General Description**

The AOD2916 uses trench MOSFET technology that is uniquely optimized to provide the most efficient high frequency switching performance. Both conduction and switching power losses are minimized due to an extremely low combination of R<sub>DS(ON)</sub>, Ciss and Coss. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

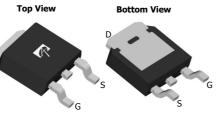
# **Product Summary**

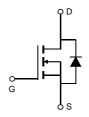
 $V_{DS}$ 100V  $I_D$  (at  $V_{GS}=10V$ ) 25A  $R_{DS(ON)}$  (at  $V_{GS}$ =10V) < 34m $\Omega$ < 43.5m $\Omega$  $R_{DS(ON)}$  (at  $V_{GS}$ =4.5V)

100% UIS Tested 100% R<sub>g</sub> Tested









Absolute Maximum Ratings T <sub>A</sub> =25℃ unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		V <sub>DS</sub>	100	V			
Gate-Source Voltage		V <sub>GS</sub>	±20	V			
Continuous Drain	T <sub>C</sub> =25℃		25				
Current	T <sub>C</sub> =100℃	I <sub>D</sub>	18	A			
Pulsed Drain Current C		I <sub>DM</sub>	50				
Continuous Drain	T <sub>A</sub> =25℃		5.5	A			
Current	T <sub>A</sub> =70℃	IDSM	4.5	^			
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	8	A			
Avalanche energy L=0.1mH <sup>C</sup>		E <sub>AS</sub>	3	mJ			
	T <sub>C</sub> =25℃	P <sub>D</sub>	50	W			
Power Dissipation <sup>B</sup>	T <sub>C</sub> =100℃	r <sub>D</sub>	25	VV			
	T <sub>A</sub> =25℃	Р	2.5	W			
Power Dissipation <sup>A</sup>	T <sub>A</sub> =70℃	P <sub>DSM</sub>	1.6	VV			
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 175	C			

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	15	20	C/W			
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	41	50	℃/W			
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	2.5	3	C/W			



#### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		100			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V				1	
	Zero date Voltage Brain durrent	T <sub>J</sub> =55℃				5	μΑ
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$		1.6	2.15	2.7	V
$I_{D(ON)}$	On state drain current	$V_{GS}$ =10V, $V_{DS}$ =5V		50			Α
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =10A			28	34	mΩ
		T <sub>J</sub> =	=125℃		51	62	11152
		$V_{GS}$ =4.5V, $I_D$ =3A			35	43.5	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=10A$			28		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.75	1	V
Is	Maximum Body-Diode Continuous Current					26	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =50V, f=1MHz			870		pF
Coss	Output Capacitance				68		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				3.5		pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			7		Ω
SWITCHI	NG PARAMETERS						
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =50V, I <sub>D</sub> =10A			12.5	20	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge				5.5	10	nC
$Q_{gs}$	Gate Source Charge				2.5		nC
$Q_{gd}$	Gate Drain Charge				2		nC
t <sub>D(on)</sub>	Turn-On DelayTime				7.5		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =50V, $R_L$ =5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			3.5		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				23		ns
t <sub>f</sub>	Turn-Off Fall Time				5.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =10A, dI/dt=500A/μs			20		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =10A, dI/dt=500A/μs			88		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The Power dissipation  $P_{DSM}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of 150°  $\,$  C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

- D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

  F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$ =175° C. The SOA curve provides a single pulse rating.
- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.

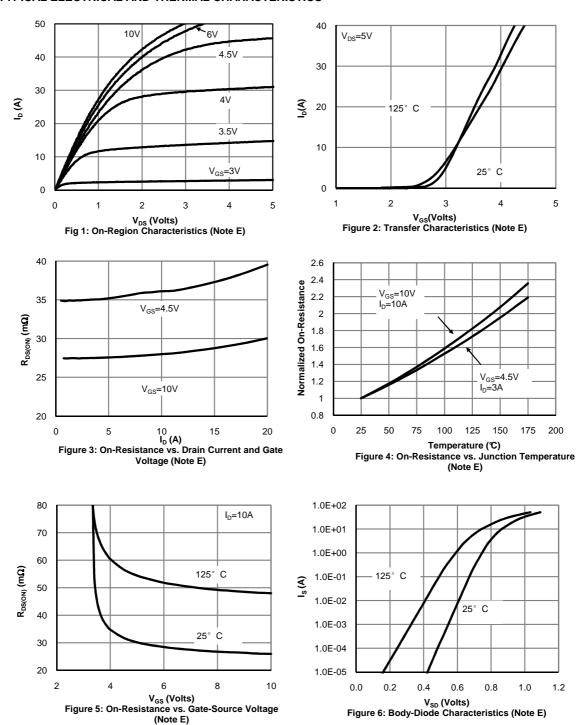
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B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=175° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25° C.

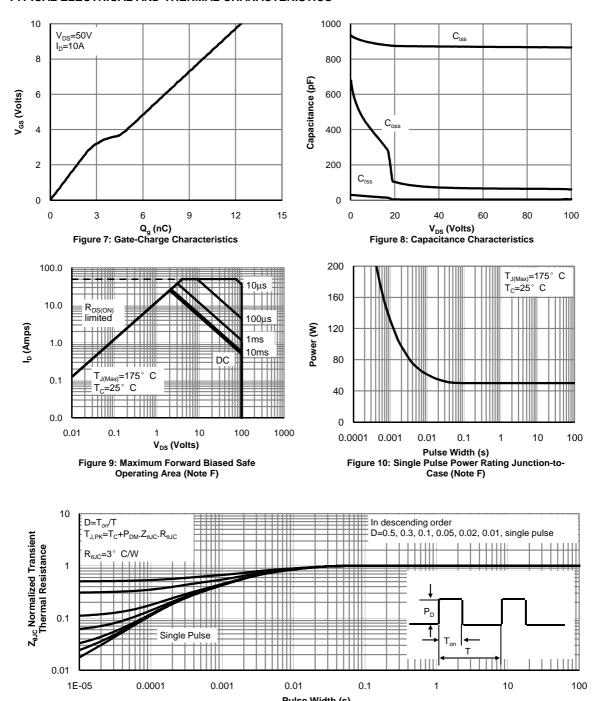


#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





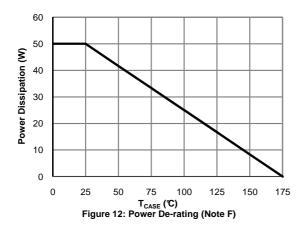
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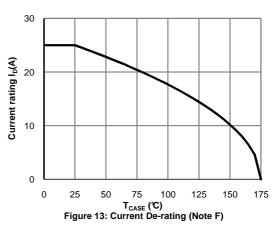


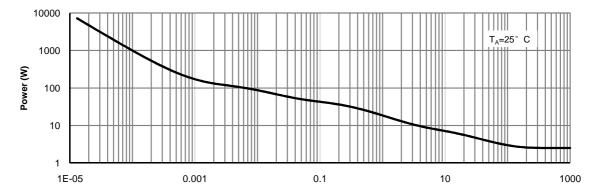
Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



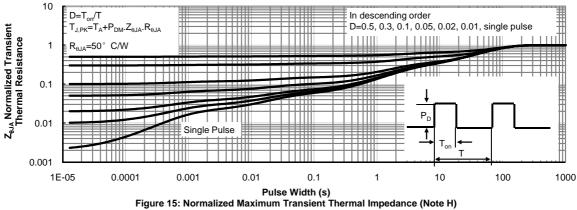
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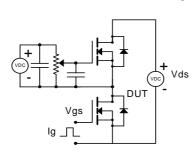
Pulse Width (s) Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

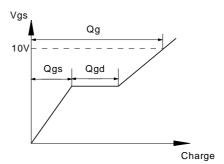


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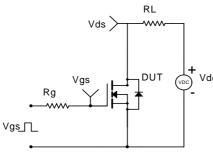


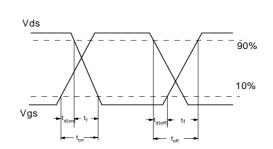
# Gate Charge Test Circuit & Waveform



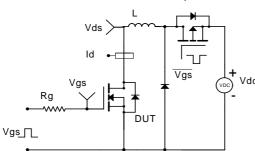


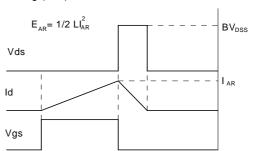
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

